



IEC 61850 Certificate Level A¹

International Usersgroup

No. 30720560-Consulting 08-0209

Issued to:
Beijing Sifang Automation CO.,LTD
Beijing Sifang Engineering CO.,LTD
Address: No.9, Shangdi 4th Street, Haidian District
Beijing, P.R.C
Zip: 100085

For the product:
CSC-326 Numerical Transformer Protection Equipment
IEC 61850 Server Version 1.10

Issued by:



The product has not shown to be non-conforming to:
IEC 61850-6, 7-1, 7-2, 7-3, 7-4 and 8-1
Communication networks and systems in substations

The conformance test has been performed according to IEC 61850-10 with product's protocol, model and technical issue implementation conformance statements: "SIFANG CSC series IED IEC61850 Protocol Implementation Conformance Statement (PICS), V1.00,CSC-P-001", "SIFANG CSC-326 IEC 61850 Modelling Implementation Conformance Statement(MICS),V1.00,CSC326-M-001" and product's extra information for testing: "SIFANG CSC series IED IEC61850 Protocol implementation extra information for testing (PIXIT),V1.00,CSC-T-001".

The following IEC 61850 conformance blocks have been tested with a positive result (number of relevant and executed test cases / total number of test cases as defined in the UCA International Users Group Device Test procedures v1.1):

1 Basic Exchange (21/23)	6 Buffered Reporting (14/15)
2+ Data Set Definition (25/28)	12a Direct Control (5/11)
3 Substitution (3/3)	12d Enhanced SBO Control (10/17)
4+ Setting Group Definition (10/10)	13 Time Synchronization (3/4)
5 Unbuffered Reporting (12/13)	14 File Transfer (5/6)

This Certificate includes a summary of the test results as carried out at KEMA in the Netherlands with UniCasim 61850 version 3.16.00 with test suite 3.16.06 and UniCA 61850 analyzer 4.15. The test is based on the UCA International Users Group Device Test Procedures version 1.1. This document has been issued for information purposes only, and the original paper copy of the KEMA report: No. 30720560-Consulting 08-0208 will prevail.

The test have been carried out on one single specimen of the products as referred above and submitted to KEMA by Beijing Sifang Automation CO.,LTD / Beijing Sifang Engineering CO.,LTD. The manufacturer's production process has not been assessed. This Certificate does not imply that KEMA has certified or approved any product other than the specimen tested.

Arnhem, January 23, 2008

S.J.L.M. Jansen
Managing Director KEMA Consulting

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Senior Test Engineer

1 Level A/- Independent Test lab with certified ISO 9000 or ISO 17025 Quality System

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Applicable Test Procedures from the UCA International Users Group Device Test Procedures version 1.1

Conformance Block	Mandatory	Conditional
1: Basic Exchange	Ass1, Ass2, Ass3, AssN2, AssN3, AssN4, AssN5 Srv1, Srv2, Srv3, Srv4, Srv5, SrvN1abcd, SrvN4	Srv6, Srv7, Srv8 SrvN1e, SrvN1f, SrvN2, SrvN3
2: Data Sets	Dset1, DsetN1ae	
2+: Data Set Definition (SCL-DynDataSet)	Dset2, Dset3, Dset4, Dset5, Dset6, Dset7, Dset8, Dset9, DsetN1cd DsetN2, DsetN3, DsetN4, DsetN5, DsetN6, DsetN7, DsetN8, DsetN9, DsetN10, DsetN11, DsetN12, DsetN13, DsetN14, DsetN15	
3: Substitution	Sub1, Sub2, SubN1	
4: Setting Group Selection	Sg1, SgN1	Sg4
4+: Setting Group Definition	Sg2, Sg3, Sg5 SgN2, SgN3, SgN4, SgN5	
5: Unbuffered Reporting	Rp1, Rp2, Rp3, Rp4, Rp7 RpN1, RpN2, RpN3, RpN4	Rp5, Rp6, RpN5
6: Buffered Reporting	Br1, Br2, Br3, Br4, Br7, Br8, Br9 BrN1, BrN2, BrN3, BrN4, BrN5	Br5, Br6
12a: Direct control	CltN3, CltN8 DOns1, DOns3	Clt2
12d: Enhanced SBO control	Clt3, CltN1, CltN2, CltN3, CltN4, CltN9 SBOes1, SBOes2, SBOes3	Clt2
13: Time sync	Tm1, Tm2, TmN1	
14: File transfer	Ft1, Ft2ab, FtN1ab	FtN1c, Ft2c